


Absolute Maximum Ratings(Note 1)

Storage Temperature
Ambient Temperature under Bias Junction Temperature under Bias $V_{C C}$ Pin Potential to Ground Pin Input Voltage (Note 2)
Input Current (Note 2)
Voltage Applied to Any Output in the Disable or
Power-Off State
in the HIGH State
Current Applied to Output
in LOW State (Max)

DC Latchup Source Current
Over Voltage Latchup (I/O)
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ -0.5 V to +7.0 V -0.5 V to +7.0 V -30 mA to +5.0 mA

$$
-0.5 \mathrm{~V} \text { to }+5.5 \mathrm{~V}
$$

$$
-0.5 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{CC}}
$$

twice the rated $\mathrm{l}_{\mathrm{OL}}(\mathrm{mA})$ $-500 \mathrm{~mA}$

## Recommended Operating

 Conditions| Free Air Ambient Temperature | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| :--- | ---: |
| Supply Voltage | +4.5 V to +5.5 V |
| Minimum Input Edge Rate $(\Delta \mathrm{V} / \Delta \mathrm{t})$ |  |
| Data Input | $50 \mathrm{mV} / \mathrm{ns}$ |
| Enable Input | $20 \mathrm{mV} / \mathrm{ns}$ |
| Clock Input | $100 \mathrm{mV} / \mathrm{ns}$ |
|  |  |
|  |  |

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

## DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | $\mathrm{V}_{\mathrm{cc}}$ | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | 2.0 |  |  | V |  | Recognized HIGH Signal |
| $\mathrm{V}_{\mathrm{IL}}$ | Input LOW Voltage |  |  | 0.8 | V |  | Recognized LOW Signal |
| $\mathrm{V}_{\mathrm{CD}}$ | Input Clamp Diode Voltage |  |  | -1.2 | V | Min | $\mathrm{I}_{\mathrm{N}}=-18 \mathrm{~mA}$ (Non I/O Pins) |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\begin{aligned} & \hline 2.5 \\ & 2.0 \end{aligned}$ |  |  |  |  | $\begin{aligned} & \mathrm{l}_{\mathrm{OH}}=-3 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) \\ & \mathrm{I}_{\mathrm{OH}}=-32 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) \end{aligned}$ |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage |  |  | 0.55 | V | Min | $\mathrm{I}_{\mathrm{OL}}=64 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| $\mathrm{V}_{\text {ID }}$ | Input Leakage Test | 4.75 |  |  | V | 0.0 | $\mathrm{I}_{\mathrm{ID}}=1.9 \mu \mathrm{~A}$ (Non-I/O Pins) <br> All Other Pins Grounded |
| $\overline{I_{H}}$ | Input HIGH Current |  |  | $\begin{aligned} & 1 \\ & 1 \end{aligned}$ | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=2.7 \mathrm{~V}(\text { Non-I/O Pins) (Note 3) } \\ & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{CC}} \text { (Non-I/O Pins) } \end{aligned}$ |
| $\mathrm{I}_{\text {BVI }}$ | Input HIGH Current Breakdown Test |  |  | 7 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {IN }}=7.0 \mathrm{~V}$ ( (Non-I/O Pins) |
| $\mathrm{I}_{\text {BVIT }}$ | Input HIGH Current Breakdown Test (1/O) |  |  | 100 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| ILL | Input LOW Current |  |  | $\begin{aligned} & \hline-1 \\ & -1 \end{aligned}$ | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=0.5 \mathrm{~V}(\text { Non-I/O Pins) (Note 3) } \\ & \mathrm{V}_{\mathrm{IN}}=0.0 \mathrm{~V} \text { (Non-I/O Pins) } \end{aligned}$ |
| $\mathrm{I}_{\mathrm{IH}+} \mathrm{I}_{\text {OZH }}$ | Output Leakage Current |  |  | 10 | $\mu \mathrm{A}$ | 0V-5.5V | $\begin{aligned} & V_{\text {OUT }}=2.7 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) ; \\ & \overline{\mathrm{OEA}} \text { or } \overline{\mathrm{OEB}}=2.0 \mathrm{~V} \end{aligned}$ |
| $I_{\text {IL }}+I_{\text {OZL }}$ | Output Leakage Current |  |  | -10 | $\mu \mathrm{A}$ | 0V-5.5V | $\begin{aligned} & \mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) ; \\ & \overline{\mathrm{OEA}} \text { or } \overline{\mathrm{OEB}}=2.0 \mathrm{~V} \end{aligned}$ |
| Ios | Output Short-Circuit Current | -100 |  | -275 | mA | Max | $\mathrm{V}_{\text {OUT }}=0 \mathrm{~V}\left(\mathrm{~A}_{n}, \mathrm{~B}_{\mathrm{n}}\right)$ |
| ${ }^{\text {CEX }}$ | Output HIGH Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}\left(\mathrm{A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| $\mathrm{I}_{\mathrm{zz}}$ | Bus Drainage Test |  |  | 100 | $\mu \mathrm{A}$ | 0.0V | $\mathrm{V}_{\text {OUT }}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{~B}_{\mathrm{n}}\right) ;$ <br> All Others GND |
| $\mathrm{I}_{\mathrm{CCH}}$ | Power Supply Current |  |  | 250 | $\mu \mathrm{A}$ | Max | All Outputs HIGH |
| $\mathrm{I}_{\text {CLL }}$ | Power Supply Current |  |  | 30 | mA | Max | All Outputs LOW |
| $\mathrm{I}_{\text {ccz }}$ | Power Supply Current |  |  | 50 | $\mu \mathrm{A}$ | Max | Outputs 3-STATE; <br> All Others GND |
| ${ }^{\text {CCT }}$ | Additional $\mathrm{I}_{\text {cc }} / \mathrm{ln}$ put |  |  | 2.5 | mA | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}-2.1 \mathrm{~V} \text {; All Others } \\ & \text { at } \mathrm{V}_{\mathrm{CC}} \text { or } \mathrm{GND} \end{aligned}$ |
| ${ }^{\text {CCD }}$ | Dynamic $\mathrm{I}_{\mathrm{CC}}$ No Load <br> (Note 4)  |  |  | 0.18 | mA/MHz | Max | Outputs Open <br> $\overline{\mathrm{OEA}}$ or $\overline{\mathrm{OEB}}=\mathrm{GND}$, <br> Non-I/O = GND or VCC <br> One Bit toggling, $50 \%$ duty cycle <br> (Note 4) |

Note 3: Guaranteed, but not tested.
Note 4: For 8-bit toggling, $\mathrm{I}_{\mathrm{CCD}}<1.4 \mathrm{~mA} / \mathrm{MHz}$.


| Extended AC Electrical Characteristics <br> (SOIC Package) |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Symbol | Parameter | $\begin{array}{r} \mathrm{T}_{\mathrm{A}}=-6 \\ \mathrm{~V}_{\mathrm{CC}}= \\ \mathrm{C} \\ 8 \text { Outp } \end{array}$ | to $+85^{\circ} \mathrm{C}$ <br> V to 5.5 V <br> 50 pF <br> Switching <br> e8) | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V} \text { to } 5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=250 \mathrm{pF} \\ \text { (Note } 9) \end{gathered}$ |  | $\begin{array}{r} \mathrm{T}_{\mathrm{A}}=-4 \\ \mathrm{~V}_{\mathrm{CC}}= \\ \mathrm{C}_{\mathrm{L}} \\ 8 \text { Outp } \end{array}$ | $+85^{\circ} \mathrm{C}$ <br> o 5.5V <br> pF <br> itching <br> 0) | Units |
|  |  | Min | Max | Min | Max | Min | Max |  |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{PLH}} \\ & \mathrm{t}_{\mathrm{PHL}} \end{aligned}$ | Propagation Delay CPA or CPB to $A_{n}$ or $B_{n}$ | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ | 6.0 6.0 | $\begin{aligned} & 2.0 \\ & 2.0 \end{aligned}$ | $\begin{aligned} & 8.0 \\ & 8.0 \end{aligned}$ | $\begin{aligned} & \hline 2.5 \\ & 2.5 \end{aligned}$ | $\begin{aligned} & \hline 10.5 \\ & 10.5 \end{aligned}$ | ns |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{PZH}} \\ & \mathrm{t}_{\mathrm{PZL}} \end{aligned}$ | Output Enable Time $\overline{\mathrm{OEA}}$ or $\overline{\mathrm{OEB}}$ to $\mathrm{A}_{\mathrm{n}}$ or $\mathrm{B}_{n}$ | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ | $\begin{aligned} & 6.0 \\ & 6.0 \end{aligned}$ | $\begin{aligned} & 2.0 \\ & 2.0 \end{aligned}$ | $\begin{aligned} & \hline 8.0 \\ & 8.0 \end{aligned}$ | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ | $\begin{aligned} & 11.5 \\ & 11.5 \end{aligned}$ | ns |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{PHZ}} \\ & \mathrm{t}_{\mathrm{PZL}} \end{aligned}$ | Output Disable Time $\overline{O E A}$ or $\overline{O E B}$ to $A_{n}$ or $B_{n}$ | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ | 6.0 6.0 | (Note 11) |  | (Note 11) |  | ns |
| Note 8: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.). <br> Note 9: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only. <br> Note 10: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. <br> Note 11: The 3-STATE delays are dominated by the RC network ( $500 \Omega, 250 \mathrm{pF}$ ) on the output and has been excluded from the datasheet. <br> Skew <br> (SOIC Package) |  |  |  |  |  |  |  |  |
| Symbol | Parameter |  | $\begin{array}{r} \hline \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.6 \\ \mathrm{C}_{\mathrm{L}}=5 \\ 8 \text { Outputs } \\ \text { (Not } \\ \mathrm{Me} \end{array}$ | $\begin{aligned} & \hline \mathrm{o}+85^{\circ} \mathrm{C} \\ & -5.5 \mathrm{~V} \\ & \mathrm{pF} \\ & \text { witching } \\ & \text { 12) } \end{aligned}$ |  | $\begin{aligned} & -40^{\circ} \mathrm{C} \text { to } \\ & =4.5 \mathrm{~V} \\ & \mathrm{~L}=250 \end{aligned}$ <br> puts Sw <br> (Note 13) <br> Max |  | Units |
| toshl <br> (Note 14) | Pin to Pin Skew HL Transitions |  |  |  |  | 1.5 |  | ns |
| tosth <br> (Note 14) | Pin to Pin Skew <br> LH Transitions |  | 1. |  |  | 2.0 |  | ns |
| $t_{P S}$ <br> (Note 15) | Duty Cycle LH-HL Skew |  | 2. |  |  | 4.5 |  | ns |
| tost <br> (Note 14) | Pin to Pin Skew LH/HL Transitions |  | 2 |  |  | 4.5 |  | ns |
| $t_{P V}$ <br> (Note 16) | Device to Device Skew LH/HL Transitions |  | 2 |  |  | 5.0 |  | ns |
| Note 12: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.). <br> Note 13: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. <br> Note 14: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW ( $\mathrm{t}_{\mathrm{OSHL}}$ ), LOW to HIGH ( $\mathrm{t}_{\mathrm{OSLH}}$ ), or any combination switching LOW-to-HIGH and/or HIGH-toLOW (tost). This specification is guaranteed but not tested. <br> Note 15: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. <br> Note 16: Propagation delay variation for a given set of conditions (i.e., temperature and $V_{C C}$ ) from device to device. This specification is guaranteed but not tested. <br> Capacitance |  |  |  |  |  |  |  |  |
| Symbo | I Parameter |  | Typ |  |  |  | ditions $=25^{\circ} \mathrm{C}$ |  |
| $\mathrm{C}_{\text {IN }}$ | Input Capacitance |  | 5 |  |  | OV (No |  |  |
| $\mathrm{C}_{\text {I/O }}$ (Note 17) | ) Output Capacitance |  | 11 |  |  | 5.0V (A |  |  |
| Note 17: $\mathrm{C}_{/ / \mathrm{O}}$ is measured at frequency $\mathrm{f}=1 \mathrm{MHz}$, per MIL-STD-883, Method 3012. |  |  |  |  |  |  |  |  |



74ABT2952 Octal Registered Transceiver
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
Package Number MTC24
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